Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/533,860	TOUCHAIS ET AL.	
Examiner	Art Unit	
Jason M. Perilla	2611	

SEARCHED				
Class	Subclass	Date	Examiner	
375	295	1/15/2008	JP .	
	296	1/15/2008	JP	
	297	.1/15/2008	JP	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
East USPAT/USPGPUB	1/15/2008	JP
Inventor Name Search EAST/EDAN	1/15/2008	JP
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